

**Search Notes****Application/Control No.**

10/814,369

**Examiner**

/Yonel Beaulieu/

**Applicant(s)/Patent under  
Reexamination**

CHEN ET AL.

**Art Unit**

3661

**SEARCHED**

Class	Subclass	Date	Examiner
701	1	4/10/2008	YB
	3		
	13-18		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Int. Search		4/10/2008	YB

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST	4/8/2008	YB
Int./Fwd+Bwd	4/10/2008	YB